SN54ACT16244, 74ACT16244 16-BIT BUFFERS/LINE DRIVERS **WITH 3-STATE OUTPUTS**

SCAS116B - MARCH 1990 - REVISED APRIL 1996

- **Members of the Texas Instruments** Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines or Buffer **Memory Address Registers**
- Flow-Through Architecture Optimizes **PCB Layout**
- Distributed V_{CC} and GND Pin **Configurations Minimize High-Speed Switching Noise**
- **EPIC™** (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at
- **Package Options Include Plastic Shrink** Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages, and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings

description

The SN54ACT16244 and 74ACT16244 are 16-bit buffers/line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. They can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. The devices provide true outputs and symmetrical OE (active-low) output-enable inputs.

SN54ACT16244... WD PACKAGE 74ACT16244 . . . DGG OR DL PACKAGE (TOP VIEW)



The 74ACT16244 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The SN54ACT16244 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74ACT16244 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each driver)

INPU	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z



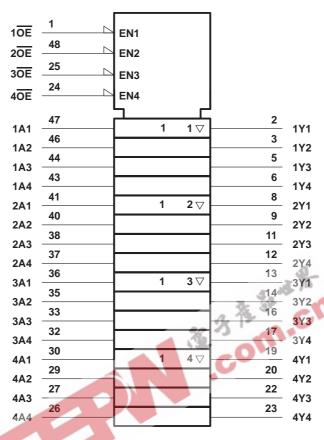
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logic symbol[†]



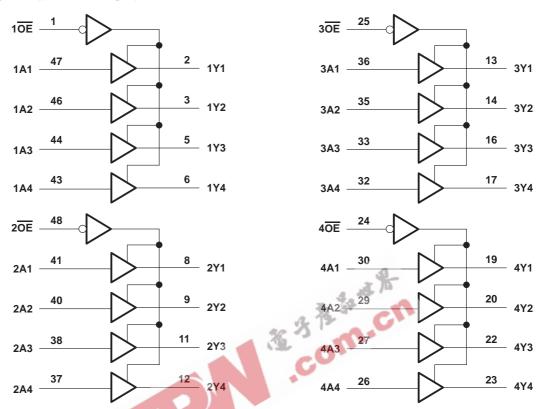
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

$\begin{array}{cccccccccccccccccccccccccccccccccccc$		
Output voltage range, V_O (see Note 1)	Supply voltage range, V _{CC}	–0.5 V to 7 V
$\begin{array}{llllllllllllllllllllllllllllllllllll$	Input voltage range, V _I (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
$\begin{array}{llllllllllllllllllllllllllllllllllll$	Output voltage range, Vo (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
$ \begin{array}{llllllllllllllllllllllllllllllllllll$	Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Continuous current through V_{CC} or GND	Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Maximum power dissipation at T _A = 55°C (in still air) (see Note 2): DGG package	Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
DL package	Continuous current through V _{CC} or GND	±400 mA
· · ·	Maximum power dissipation at T _A = 55°C (in still air) (see Note 2): DGG package	0.85 W
Storage temperature range, T _{stg} –65°C to 150°C	DL package	1.2 W
	Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150 °C and a board trace length of 750 mils.



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recommended operating conditions (see Note 3)

		SN54AC	T16244	74ACT	UNIT	
		MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage (see Note 4)	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
V _{IL}	Low-level input voltage		0.8		0.8	V
٧ _I	Input voltage	0	Vcc	0	Vcc	V
VO	Output voltage	0	Vcc	0	VCC	V
ЮН	High-level output current		-24		-24	mA
loL	Low-level output current		24		24	mA
Δt/Δν	Input transition rise or fall rate	0	10	0	10	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTES: 3. Unused inputs should be tied to V_{CC} through a pullup resistor of approximately 5 k Ω or greater to prevent them from floating.

4. All V_{CC} and GND pins must be connected to the proper voltage supply.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T	√ = 25°C	SN54ACT16244		74ACT16244		UNIT
PARAMETER		VCC	MIN	TYP MAX	MIN	MAX	MIN	MAX	UNII
	Ι _{ΟΗ} = –50 μΑ	4.5 V	4.4	37	4.4		4.4		
	ΙΟΗ = -50 μΑ	5.5 V	5.4	-01	5.4		5.4		
\/o	1011 = 24 mA	4.5 V	3.94	9	3.7		3.8		V
Voн	I _{OH} = -24 mA	5.5 V	4.94		4.7		4.8		V
	I _{OH} = -50 mA [†]	5.5 V			3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5. 5 V					3.85		
	I _{OL} = 50 µA	4.5 V		0.1		0.1		0.1	V
		5.5 V		0.1		0.1		0.1	
Val	I _{OL} = 24 mA	4.5 V		0.36		0.5		0.44	
VOL		5.5 V		0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V				1.65			
	I _{OL} = 75 mA [†]	5.5 V						1.65	
lį	$V_I = V_{CC}$ or GND	5.5 V		±0.1		±1		±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V		±0.5		±10		±5	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V		8		160		80	μΑ
ΔI _{CC} ‡	One input at 3.4 V, Other inputs at GND or V _{CC}	5.5 V		0.9		1		1	mA
Ci	$V_I = V_{CC}$ or GND	5 V		4.5					pF
Co	$V_O = V_{CC}$ or GND	5 V		13.5					pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.



[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

PARAMETER								
	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			MIN	MAN	UNIT
	(1141 01)		MIN	TYP	MAX	IVIIIN	MAX	
^t PLH	Α	A Y	4	6.5	8.5	3	10.3	ns
^t PHL			3.4	6.3	8.7	3.4	3.4 10.1	
^t PZH	- OE	V	3	5.8	8.1	3	10.5	no
^t PZL		Ĭ	3.7	6.7	9.3	3.7	11	ns
^t PHZ	<u> </u>		5.4	8.1	11.5	5.4	13	ne
t _{PLZ}	OE	ſ	5	7.5	9.5	5	10.9	ns

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

			74ACT16244					
PARAMETER	FROM (INPUT)	TO (OUTPUT)	T _A = 25°C			MIN	MAX	UNIT
	(01)	(331.31)	MIN	TYP	MAX	IVIIIA	IVIAA	
^t PLH	А	V 3-34	4	6.5	8.5	4	9.4	ne
^t PHL	A	2.19	3.4	6.3	8.7	3.4	9.5	ns
^t PZH	ŌĒ	V	3	5.8	8.1	3	8.9	ne
t _{PZL}	ÜE	~ B ~O	3.7	6.7	9.3	3.7	10.3	ns
^t PHZ	ŌĒ	V.*	5.4	8.1	10.3	5.4	11.3	ne
^t PLZ	OE OE		5	7.5	9.5	5	10.3	ns

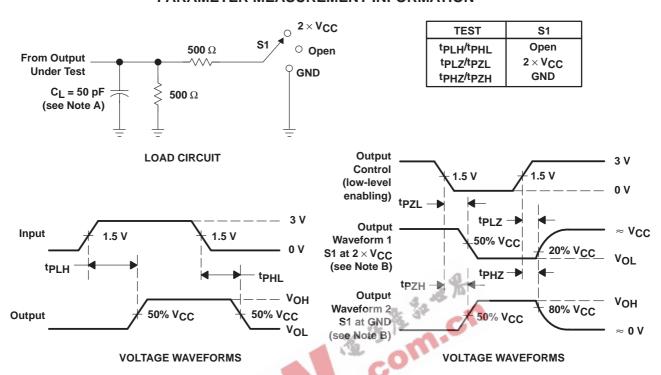
operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25 ^{\circ}\text{C}$

PARAMETER			TEST CO	TYP	UNIT
C _{pd} Power dissipation capacitance	Outputs enabled	C 50 pE	f = 1 MHz	39	nE.
	Outputs disabled	$C_L = 50 \text{ pF},$	I = I IVIDZ	11	pF

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f = 3$ ns. $t_f = 3$ ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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